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| U.S. Department of Commerce, Patent and Trademark INFORMATION DISCLOSURE STATEMENT BY APPLICANT | | Atty. Docket No. | Application No. | | | | |
|---|-------------------------------|------------------|-----------------|-------|----------|----------------------------|--|
| | | TNCR.169US2 | 10/729,609 | | | | |
| (Use several sheets if necessary) | | Applicant(s) | Conf. No. | | | | |
| | | Thomas McWaid | 2888 | | | | |
| | | Filing Date | Group | | | | |
| | | December 5, 2003 | 2856 | | | | |
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| (Use several sheets if necessary) | | Applicant(s) Thomas McWaid | Conf. No. 2888 |
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